

EAST SEARCH

1/11/06

L#	Hits	Search String	Databases
S1	566094	(integrated or digital) near2 circuit\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S2	40	S1 and ((bus near2 (performance or traffic)) with (simulat\$3 or evaluat\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S3	1665	S1 and (bus with (simulat\$3 or evaluat\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S4	2232	S1 and (bus near2 (performance or traffic))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S5	210	S3 and S4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S6	210	S2 or S5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S7	23	S6 and (high near2 level near2 language\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S8	173	S6 and (source\$1 or algorithm)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S9	88	S6 and (source\$1 and algorithm)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S10	27	S6 and (bus with hardware with software)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S11	156	S6 and (bus with data with transfer\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S12	8	S6 and (evaluation with function\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S13	11	S6 and (modifi\$3 with source\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S14	1	S6 and ("general purpose" near2 language\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S15	60	S6 and (architecture with design)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S16	55	S11 and S15	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S17	24	S6 and (bus with process\$3 with rate\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S18	2	S6 and (bus with traffic\$3 with rate\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S19	132	S6 and (bus with traffic\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S20	11	S6 and (high near2 level near2 design\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S21	1	S6 and (performance or verification with (feed\$3 near2 back))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S22	1	S6 and (evaluation or verification with (feed\$3 near2 back))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S23	24	S6 and (feed\$3 near2 back)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S24	1	S6 and (syntax with (correction or analysis))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S25	103	S7 or S9 or S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S26	72	S12 or S13 or S16	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S27	7	S17 and S19	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S28	51	S17 or S20 or S23 or S27	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S30	3687	S3 or S4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S31	10	S30 and (syntax with (correction or analysis))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S29	138	S25 or S26 or S28	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S32	566094	(integrated or digital) near2 circuit\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S33	40	S32 and ((bus near2 (performance or traffic)) with (simulat\$3 or evaluat\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S34	1665	S32 and (bus with (simulat\$3 or evaluat\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S35	2232	S32 and (bus near2 (performance or traffic))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S36	210	S34 and S35	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S37	210	S33 or S36	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S38	8	S37 and (evaluation with function\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S39	10	S37 and (bus with "data transfer" with evaluation)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S40	11	S37 and (high near2 level near2 design\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S41	11	S37 and (modifi\$3 with source\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S42	24	S37 and (bus with process\$3 with rate\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S43	5	S37 and (bus with processing with rate\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S44	3687	S34 or S35	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S45	7	S44 and (bus with "processing rate")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S47	3	S44 and ("high level" near2 design\$1) with performance)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S46	55	S44 and ("high level" near2 design\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

S48	24	S37 and (feed\$3 near2 back)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S49	70	S44 and ((bus near2 performance) with (feedback\$3 or (feed near2 back)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S50	943	S32 and (bus with simulat\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S51	703	S50 and (source\$1 or (programming near2 language\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S52	168	S51 and (bus with (performance or evaluat\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S53	83	S52 and (hardware with software)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S54	403	S50 and (language\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S55	62	S53 and S54	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S56	1	S50 and ("bus traffic" with (count\$3 or increment\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S57	1	S50 and (bus with traffic with (count\$3 or increment\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S58	1	S50 and (bus with evaluation with increment\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S59	45	((integrated or digital) near2 circuit\$1) with ("architecture design")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S60	4890	((integrated or digital) near2 circuit\$1) with simulat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S62	5	((integrated or digital) near2 circuit\$1) with co-simulat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S63	17	((integrated or digital) near2 circuit\$1) same co-simulat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S64	4939	S59 or S60 or S63	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S65	56	S64 and (bus near2 (traffic or performance or "data transfer"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S66	161	S64 and ((partition\$3 or allocat\$3) with (hardware or software))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S67	13	S64 and (bus near2 ((process\$3 near2 rate) or rate))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S68	40	S64 and ((algorithm or application) with "source code")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S69	0	S64 and (profil\$3 with "source code")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S70	0	S64 and (profil\$3 with "data transfer")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S71	117	S64 and (profil\$3 with (simulat\$3 or bus))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S72	4	S66 and S71	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S73	333	S65 or S66 or S67 or S68 or S71 or S72	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S74	753	((integrated or digital) near2 circuit\$1) and ("architecture design")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S75	5612	S64 or S74	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S78	84	S75 and (bus near2 (traffic or performance or "data transfer"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S79	228	S75 and ((partition\$3 or allocat\$3) with (hardware or software))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S80	31	S75 and (bus near2 ((process\$3 near2 rate) or rate))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S81	71	S75 and ((algorithm or application) with "source code")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S82	0	S75 and (profil\$3 with "source code")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S83	1	S75 and (profil\$3 with "data transfer")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S84	125	S75 and (profil\$3 with (simulat\$3 or bus))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S85	7	S79 and S84	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S86	446	S78 or S79 or S80 or S81 or S83 or S84 or S85	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S87	17	S75 and (profil\$3 with software)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S88	45	((integrated or digital) near2 circuit\$1) with ("architecture design")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S89	4890	((integrated or digital) near2 circuit\$1) with simulat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S90	17	((integrated or digital) near2 circuit\$1) same co-simulat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S91	4939	S88 or S89 or S90	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S92	753	((integrated or digital) near2 circuit\$1) and ("architecture design")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S93	5612	S91 or S92	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S94	84	S93 and (bus near2 (traffic or performance or "data transfer"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S95	228	S93 and ((partition\$3 or allocat\$3) with (hardware or software))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S96	31	S93 and (bus near2 ((process\$3 near2 rate) or rate))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S97	71	S93 and ((algorithm or application) with "source code")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S98	1	S93 and (profil\$3 with "data transfer")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S99	125	S93 and (profil\$3 with (simulat\$3 or bus))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S100	7	S95 and S99	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S101	446	S94 or S95 or S96 or S97 or S98 or S99 or S100	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
S102	131	S93 and (bus near2 (traffic or performance or "data transfer"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

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1/11/06

Results of search set L29:S25 or S26 or S28

Document Kind	Codes Title	Issue Date	Current OR	Abstract
US 20050128489 A1	Parametric optimization of optical metrology model	20050616	356/601	
US 20050122500 A1	System and method for lithography simulation	20050609	355/67	
US 20050120327 A1	System and method for lithography simulation	20050602	716/20	
US 20050120012 A1	Adaptive hierarchy usage monitoring HVAC control system	20050602	707/3	
US 20050108667 A1	METHOD FOR DESIGNING AN INTEGRATED CIRCUIT HAVING MULTIPLE VOLTAGE DOF	20050519	716/4	
US 20050102125 A1	Inter-chip communication system	20050512	703/14	
US 20050097500 A1	System and method for lithography simulation	20050505	716/20	
US 20050094729 A1	Software and hardware partitioning for multi-standard video compression and decompression	20050505	375/240.16	
US 20050091633 A1	System and method for lithography simulation	20050428	716/20	
US 20050086565 A1	System and method for generating a test case	20050421	714/741	
US 20050081170 A1	Method and apparatus for accelerating the verification of application specific integrated circuit	20050414	716/6	
US 20050081130 A1	Using constrained scan cells to test integrated circuits	20050414	714/726	
US 20050076322 A1	System and method for lithography simulation	20050407	716/20	
US 20050076282 A1	System and method for testing a circuit design	20050407	714/739	
US 20050071706 A1	Slew rate control mechanism	20050331	713/503	
US 20050065762 A1	ESD protection device modeling method and ESD simulation method	20050324	703/14	
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US 20050042527 A1	Phase shift mask including sub-resolution assist features for isolated spaces	20050224	430/5	
US 20050039156 A1	Design method for essentially digital systems and components thereof and essentially digital s	20050217	716/18	
US 20050025054 A1	Extensible traffic generator for synthesis of network data traffic	20050203	370/235	
US 20050015778 A1	Method and system for expressing the algorithms for the manipulation of hardware state using	20050120	719/321	
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US 20040243959 A1	Design method for semiconductor integrated circuit device	20041202	716/7	
US 20040236876 A1	Apparatus and method of memory access control for bus masters	20041125	710/22	
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US 20040214150 A1	Interaction education system for teaching patient care	20041028	434/273	
US 20040209169 A1	Method of Verifying the Placement of Sub-Resolution Assist Features in a Photomask Layout	20041021	430/5	
US 20040204928 A1	Simulator apparatus and related technology	20041014	703/13	
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US 20040153301 A1	Input pipeline registers for a node in an adaptive computing engine	20040826	712/220	
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US 20040145033 A1	Integrated circuit devices and methods and apparatuses for designing integrated circuit device	20040729	703/22	
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US 20040131267 A1	Method and apparatus for performing quality video compression and motion estimation	20040708	382/236	
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US 20040123256 A1	Software traffic generator/analyser	20040624	716/4	
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US 20030188299 A1	Method and apparatus for simulation system compiler	20031002 717/141
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US 20020194572 A1	Methods and apparatuses for designing integrated circuits	20021219 716/1
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US 20020108092 A1	Digital circuit design method using programming language	20020808 716/1
US 20020097216 A1	Animated video device with synchronized voice	20020725 345/108
US 20020095304 A1	System, method, and apparatus for storing emissions and susceptibility information	20020718 705/1
US 20020087940 A1	Method for designing large standard-cell based integrated circuits	20020704 716/2
US 20020087939 A1	Method for designing large standard-cell based integrated circuits	20020704 716/2
US 20020066082 A1	Bus performance evaluation method for algorithm description	20020530 717/135
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US 20020019989 A1	Hardware and software co-simulation including simulating the cache of a target processor	20020214 716/5
US 20020016704 A1	Adjoint sensitivity determination for nonlinear circuit models	20020207 703/14
US 20020016674 A1	Golf course yardage and information system having improved zone information and display ch	20020207 701/215
US 20020013918 A1	Devices, systems and methods for mode driven stops	20020131 714/30
US 20020011949 A1	Golf course yardage and information system with zone detection	20020131 342/357.06
US 20020010544 A1	Display monitor for golf cart yardage and information system	20020124 701/213
US 20020004927 A1	Method for designing integrated circuit	20020110 716/2
US 20010056341 A1	Method and apparatus for debugging programs in a distributed environment	20011227 703/22
US 20010049593 A1	Software tool to allow field programmable system level devices	20011206 703/14
US 20010039640 A1	Method and apparatus for wiring integrated circuits with multiple power buses based on perfor	20011108 716/2
US 20010037424 A1	Snoop phase in a highly pipelined bus architecture	20011101 710/220
US 20010037421 A1	Enhanced highly pipelined bus architecture	20011101 710/305
US 20010029601 A1	Semiconductor device analyzer, method for analyzing/manufacturing semiconductor device, an	20011011 716/19
US 20010012014 A1	SINGLE LOGICAL IN X WINDOWS WITH DIRECT HARDWARE ACCESS TO THE FRAME I	20010809 345/541
US 20010011212 A1	METHOD AND APPARATUS FOR GATE-LEVEL SIMULATION OF SYNTHESIZED REGISTE	20010802 703/22
US 6907487 B2	Enhanced highly pipelined bus architecture	20050614 710/305
US 6892362 B1	Hybrid state machine	20050510 716/1
US 6891626 B2	Caching of intra-layer calculations for rapid rigorous coupled-wave analyses	20050510 356/625
US 6885946 B1	Method and apparatus for performing image process of seismic data	20050426 702/16
US 6880031 B2	Snoop phase in a highly pipelined bus architecture	20050412 710/305
US 6873720 B2	System and method of providing mask defect printability analysis	20050329 382/149
US 6871298 B1	Method and apparatus that simulates the execution of parallel instructions in processor functi-	20050322 714/33
US 6859831 B1	Method and apparatus for internetworked wireless integrated network sensor (WINS) nodes	20050222 709/224
US 6854048 B1	Speculative execution control with programmable indicator and deactivation of multiaccess re	20050208 712/216
US 6846120 B2	System for printing information on a mailing medium	20050125 400/611
US 6845494 B2	Method for generating design constraints for modules in a hierarchical integrated circuit desi	20050118 716/6
US 6845489 B1	Database for design of integrated circuit device and method for designing integrated circuit de	20050118 716/1
US 6842714 B1	Method for determining the leakage power for an integrated circuit	20050111 702/136
US 6842035 B2	Apparatus and method for bus signal termination compensation during detected quiet cycle	20050111 326/30

US 6834380 B2	Automated EMC-driven layout and floor planning of electronic devices and systems	20041221 716/10
US 6834375 B1	System and method for product yield prediction using a logic characterization vehicle	20041221 716/2
US 6832251 B1	Method and apparatus for distributed signal processing among internetworked wireless integr	20041214 709/224
US 6826607 B1	Apparatus for internetworked hybrid wireless integrated network sensors (WINS)	20041130 709/224
US 6826517 B2	Method and apparatus for simulating manufacturing, electrical and physical characteristics of	20041130 703/2
US 6825052 B2	Test assembly including a test die for testing a semiconductor product die	20041130 438/15
US 6811935 B2	Phase shift mask layout process for patterns including intersecting line segments	20041102 430/5
US 6810442 B1	Memory mapping system and method	20041026 710/22
US 6810372 B1	Multimodal optimization technique in test generation	20041026 703/13
US 6804735 B2	Response and data phases in a highly pipelined bus architecture	20041012 710/112
US 6801220 B2	Method and apparatus for adjusting subpixel intensity values based upon luminance character	20041005 345/694
US 6792563 B1	Method and apparatus for bus activity tracking	20040914 714/43
US 6792328 B2	Metrology diffraction signal adaptation for tool-to-tool matching	20040914 700/121
US 6785876 B2	Design method for semiconductor integrated circuit device	20040831 716/7
US 6785873 B1	Emulation system with multiple asynchronous clocks	20040831 716/4
US 6779157 B2	Semiconductor integrated circuit manufacturing method and model parameter extracting meth	20040817 716/2
US 6777141 B2	Phase shift mask including sub-resolution assist features for isolated spaces	20040817 430/5
US 6766419 B1	Optimization of cache evictions through software hints	20040720 711/133
US 6760866 B2	Process of operating a processor with domains and clocks	20040706 714/34
US 6760478 B1	Method and apparatus for performing two pass quality video compression through pipelining a	20040706 382/236
US 6758676 B2	Interactive education system for teaching patient care	20040706 434/262
US 6757645 B2	Visual inspection and verification system	20040629 703/13
US 6754763 B2	Multi-board connection system for use in electronic design automation	20040622 710/317
US 6751583 B1	Hardware and software co-simulation including simulating a target processor using binary tra	20040615 703/17
US 6742165 B2	System, method and computer program product for web-based integrated circuit design	20040525 716/1
US 6735743 B1	Method and apparatus for invalid state detection	20040511 716/4
US 6735630 B1	Method for collecting data using compact internetworked wireless integrated network sensors	20040511 709/224
US 6734509 B2	Semiconductor integrated circuit	20040511 257/393
US 6732350 B1	Local naming for HDL compilation	20040504 716/18
US 6721691 B2	Metrology hardware specification using a hardware simulator	20040413 702/189
US 6718429 B1	Configurable register file with multi-range shift register support	20040406 711/101
US 6711729 B1	Methods and apparatuses for designing integrated circuits using automatic reallocation techni	20040323 716/18
US 6704895 B1	Integrated circuit with emulation register in JTAG JAP	20040309 714/726
US 6697773 B1	Using assignment decision diagrams with control nodes for sequential review during behavio	20040224 703/15
US 6694488 B1	System for the design of high-performance communication architecture for system-on-chips u	20040217 716/1
US 6675139 B1	Floor plan-based power bus analysis and design tool for integrated circuits	20040106 703/17
US 6671818 B1	Problem isolation through translating and filtering events into a standard object format in a net	20031230 714/4
US 6668364 B2	Methods and apparatuses for designing integrated circuits	20031223 716/7
US 6668356 B2	Method for designing circuits with sections having different supply voltages	20031223 716/1
US 6668337 B2	Method for designing integrated circuit based on the transaction analyzing model	20031223 714/6
US 6658633 B2	Automated system-on-chip integrated circuit design verification system	20031202 716/5
US 6651225 B1	Dynamic evaluation logic system and method	20031118 716/4
US 6640249 B1	Presentation services patterns in a network environment	20031028 709/228
US 6640248 B1	Application-aware, quality of service (QoS) sensitive, media access control (MAC) layer	20031028 709/226
US 6640244 B1	Request batcher in a transaction services patterns environment	20031028 709/207
US 6640238 B1	Activity component in a presentation services patterns environment	20031028 709/201
US 6636242 B2	View configurer in a presentation services patterns environment	20031021 715/764
US 6629296 B1	Functional verification of integrated circuit designs	20030930 716/5
US 6624078 B1	Methods for analyzing the effectiveness of wafer backside cleaning	20030923 438/692
US 6615389 B1	Database for designing integrated circuit device, and method for designing integrated circuit d	20030902 716/1
US 6615253 B1	Efficient server side data retrieval for execution of client side applications	20030902 709/219
US 6615199 B1	Abstraction factory in a base services pattern environment	20030902 706/50
US 6610449 B2	Phase shift masking for "double-T" intersecting lines	20030826 430/5
US 6606744 B1	Providing collaborative installation management in a network-based supply chain environment	20030812 717/174

US 6606721 B1	Method and apparatus that tracks processor resources in a dynamic pseudo-random test prog	20030812 714/728
US 6606660 B1	Stream-based communication in a communication services patterns environment	20030812 709/227
US 6606609 B1	Apparatus and method for operating an integrated circuit	20030812 706/1
US 6606588 B1	Design apparatus and a method for generating an implementable description of a digital syste	20030812 703/15
US 6604230 B1	Multi-logic device systems having partial crossbar and direct interconnection architectures	20030805 716/16
US 6601234 B1	Attribute dictionary in a business logic services environment	20030729 717/108
US 6601192 B1	Assertion component in environment services patterns	20030729 714/38
US 6578188 B1	Method and apparatus for a network-based mask defect printability analysis system	20030610 716/19
US 6578187 B2	Digital circuit design method using programming language	20030610 716/18
US 6578068 B1	Load balancer in environment services patterns	20030610 709/203
US 6571282 B1	Block-based communication in a communication services patterns environment	20030527 709/219
US 6567967 B2	Method for designing large standard-cell base integrated circuits	20030520 716/10
US 6551844 B1	Test assembly including a test die for testing a semiconductor product die	20030422 438/14
US 6550057 B1	Piecemeal retrieval in an information services patterns environment	20030415 717/126
US 6549949 B1	Fixed formal stream in a communication services patterns environment	20030415 709/236
US 6546505 B1	Processor condition sensing circuits, systems and methods	20030408 714/30
US 6541165 B1	Phase shift mask sub-resolution assist features	20030401 430/5
US 6539522 B1	Method of developing re-usable software for efficient verification of system-on-chip integrated	20030325 716/5
US 6539497 B2	IC with selectively applied functional and test clocks	20030325 714/30
US 6539396 B1	Multi-object identifier system and method for information service pattern environment	20030325 707/103R
US 6529948 B1	Multi-object fetch component	20030304 709/217
US 6529909 B1	Method for translating an object attribute converter in an information services patterns environi	20030304 707/10
US 6526462 B1	Programmable multi-tasking memory management system	20030225 710/242
US 6525690 B2	Golf course yardage and information system with zone detection	20030225 430/5
US 6524752 B1	Phase shift masking for intersecting lines	20030218 716/10
US 6523157 B1	Method for designing integrated circuit device and database for design of integrated circuit dev	20030218 702/117
US 6522985 B1	Emulation devices, systems and methods utilizing state machines	20030211 716/18
US 6519754 B1	Methods and apparatuses for designing integrated circuits	20030211 716/3
US 6519742 B1	Local naming for HDL compilation	20030128 716/7
US 6513146 B1	Method of designing semiconductor integrated circuit device, method of analyzing power cons	20030107 703/2
US 6505147 B1	Method for process simulation	20030107 430/5
US 6503666 B1	Phase shift masking for complex patterns	20030107 434/262
US 6503087 B1	Interactive education system for teaching patient care	20021231 714/49
US 6502213 B1	System, method, and article of manufacture for a polymorphic exception handler in environmei	20021217 709/203
US 6496850 B1	Clean-up of orphaned server contexts	20021210 716/18
US 6493863 B1	Method of designing semiconductor integrated circuit	20021210 710/309
US 6493784 B1	Communication device, multiple bus control device and LSI for controlling multiple bus	20021203 710/110
US 6490842 B1	Locked read/write on separate address/data bus using write barrier	20021126 716/4
US 6487701 B1	System and method for AC performance tuning by threshold voltage shifting in tubbed semic	20021119 716/20
US 6484305 B1	Impurity quantity transfer device enabling reduction in pseudo diffusion error generated at inter	20021119 716/18
US 6484304 B1	Method of generating application specific integrated circuits using a programmable hardware	20021105 714/39
US 6477665 B1	System, method, and article of manufacture for environment services patterns in a netcentric e	20021105 709/231
US 6477580 B1	Self-described stream in a communication services patterns environment	20021022 716/21
US 6470489 B1	Design rule checking system and method	20021022 716/6
US 6470482 B1	METHOD AND SYSTEM FOR CREATING, DERIVING AND VALIDATING STRUCTURAL DE	20021015 710/117
US 6470242 B1	Display monitor for golf cart yardage and information system	20020924 710/306
US 6467003 B1	Fault tolerant data communication network	20020917 716/8
US 6457089 B1	Microprocessor bus structure	20020910 716/11
US 6453452 B1	Method and apparatus for data hierarchy maintenance in a system for mask description	20020903 716/2
US 6449761 B1	Method and apparatus for providing multiple electronic design solutions	20020827 717/108
US 6446239 B1	Method and apparatus for optimizing electronic design	20020820 716/7
US 6442748 B1	System, method and article of manufacture for a persistent state and persistent object separat	20020820 709/225
US 6438735 B1	Methods and apparatuses for designing integrated circuits	
US 6438594 B1	Delivering service to a client via a locally addressable interface	

US 6434628 B1	Common interface for handling exception interface name with additional prefix and suffix for h;	20020813 714/48
US 6434568 B1	Information services patterns in a netcentric environment	20020813 707/103R
US 6429029 B1	Concurrent design and subsequent partitioning of product and test die	20020806 438/14
US 6427226 B1	Selectively reducing transistor channel length in a semiconductor device	20020730 716/10
US 6427224 B1	Method for efficient verification of system-on-chip integrated circuit designs including an embed	20020730 716/4
US 6421251 B1	Array board interconnect system and method	20020716 361/788
US 6417849 B2	Single logical screen in X windows with direct hardware access to the frame buffer for 3D rent	20020709 345/419
US 6412101 B1	Simultaneous path optimization (SPO) system and method	20020625 716/10
US 6389586 B1	Method and apparatus for invalid state detection	20020514 716/18
US 6389577 B1	Analyzing CMOS circuit delay	20020514 716/4
US 6389498 B1	Microprocessor having addressable communication port	20020514 710/268
US 6389379 B1	Conversion system and method	20020514 703/14
US 6370679 B1	Data hierarchy layout correction and verification method and apparatus	20020409 716/19
US 6370492 B1	Modified design representation for fast fault simulation of an integrated circuit	20020409 703/13
US 6367056 B1	Method for incremental timing analysis	20020402 716/5
US 6356945 B1	Method and apparatus including system architecture for multimedia communications	20020312 709/231
US 6349392 B1	Devices, systems and methods for mode driven stops	20020219 714/30
US 6339836 B1	Automated design partitioning	20020115 716/5
US 6336087 B1	Method and apparatus for gate-level simulation of synthesized register transfer level design wi	20020101 703/15
US 6324678 B1	Method and system for creating and validating low level description of electronic design	20011127 716/18
US 6321366 B1	Timing-insensitive glitch-free logic system and method	20011120 716/6
US 6314552 B1	Electronic design creation through architectural exploration	20011106 716/18
US 6311310 B1	Method and apparatus for wiring integrated circuits with multiple power buses based on perfor	20011030 716/2
US 6311147 B1	Integrated circuit power net analysis	20011030 703/18
US 6311146 B1	Circuit simulation with improved circuit partitioning	20011030 703/14
US 6305006 B1	Generating candidate architectures for an architectural exploration based electronic design cr	20011016 716/18
US 6304834 B1	Method and apparatus for semiconductor device simulation with linearly changing quasi-fermi p	20011016 703/4
US 6295546 B1	Method and apparatus for eliminating the transpose buffer during a decomposed forward or in	20010925 708/402
US 6295517 B1	Method and apparatus for adaptively or selectively choosing event-triggered cycle-based simul	20010925 703/15
US 6292589 B1	Method for choosing rate control parameters in motion-compensated transform-based picture	20010918 382/239
US 6285970 B1	Computer simulation method of silicon oxidation	20010904 703/2
US 6272451 B1	Software tool to allow field programmable system level devices	20010807 703/13
US 6263484 B1	Prototyping system and a method of operating the same	20010717 716/18
US 6240376 B1	Method and apparatus for gate-level simulation of synthesized register transfer level designs v	20010529 703/15
US 6240375 B1	Method of simulating an integrated circuit for error correction in a configuration model, and a c	20010529 703/14
US 6236940 B1	Display monitor for golf cart yardage and information system	20010522 701/300
US 6236360 B1	Golf course yardage and information system	20010522 342/357.13
US 6233540 B1	Design environment and a method for generating an implementable description of a digital sys	20010515 703/14
US 6233361 B1	Topography processor system	20010515 382/260
US 6216252 B1	Method and system for creating, validating, and scaling structural description of electronic dev	20010410 716/1
US 6212493 B1	Profile directed simulation used to target time-critical crossproducts during random vector test	20010403 703/22
US 6212487 B1	Method and apparatus of establishing a region to be made amorphous	20010403 703/12
US 6208954 B1	Method for scheduling event sequences	20010327 703/16
US 6195790 B1	Electrical parameter evaluation system, electrical parameter evaluation method, and computer	20010227 716/20
US 6193152 B1	Modular signature and data-capture system and point of transaction payment and reward syst	20010227 235/380
US 6191663 B1	Echo reduction on bit-serial, multi-drop bus	20010220 333/17.3
US 6178533 B1	Method and system for design verification	20010123 714/739
US 6173240 B1	Multidimensional uncertainty analysis	20010109 703/2
US 6167491 A	High performance digital electronic system architecture and memory circuit therefor	20001226 711/149
US 6150724 A	Multi-chip semiconductor device and method for making the device by using multiple flip chip i	20001121 257/777
US 6134516 A	Simulation server system and method	20001017 703/27
US 6128718 A	Apparatus and method for a base address register on a computer peripheral device supportin	20001003 711/212
US 6117182 A	Optimum buffer placement for noise avoidance	20000912 716/8
US 6101276 A	Method and apparatus for performing two pass quality video compression through pipelining a	20000808 382/236

US 6085336 A	Data processing devices, systems and methods with mode driven stops	2000704 714/30
US 6078745 A	Method and apparatus for size optimization of storage units	2000620 717/151
US 6072994 A	Digitally programmable multifunction radio system architecture	2000606 455/84
US 6067041 A	Moving target simulator	2000523 342/171
US 6061222 A	Method and apparatus for reducing noise in integrated circuit chips	2000509 361/111
US 6052706 A	Apparatus for performing fast multiplication	2000418 708/631
US 6038383 A	Method and apparatus for determining signal line interconnect widths to ensure electromigration	20000314 716/5
US 6032268 A	Processor condition sensing circuits, systems and methods	2000229 714/30
US 6026230 A	Memory simulation system and method	20000215 703/13
US 6026217 A	Method and apparatus for eliminating the transpose buffer during a decomposed forward or in	2000215 709/247
US 6023573 A	Apparatus and method for analyzing circuits using reduced-order modeling of large linear sub	20000208 703/2
US 6021266 A	Method of designing an integrated circuit using scheduling and allocation with parallelism and	20000201 716/2
US 6014570 A	Efficient radio signal diversity combining using a small set of discrete amplitude and phase ve	20000111 455/500
US 6009256 A	Simulation/emulation system and method	19991228 703/13
US 6009255 A	Method of deposition profile simulation	19991228 703/6
US 6002861 A	Method for performing simulation using a hardware emulation system	19991214 703/16
US 5995080 A	Method and apparatus for interleaving and de-interleaving YUV pixel data	19991130 345/603
US 5991863 A	Single carry/borrow propagate adder/decrementer for generating register stack addresses in a	19991123 711/219
US 5991533 A	Verification support system	19991123 703/28
US 5966312 A	Method for monitoring and analyzing manufacturing processes using statistical simulation wit	19991012 703/6
US 5949994 A	Dedicated context-cycling computer with timed context	19990907 712/228
US 5937179 A	Integrated circuit design system with shared hardware accelerator and processes of designing	19990810 716/16
US 5933356 A	Method and system for creating and verifying structural logic model of electronic design from t	19990803 703/15
US 5911059 A	Method and apparatus for testing software	19990608 703/23
US 5910897 A	Specification and design of complex digital systems	19990608 716/19
US 5907853 A	Method and apparatus for maintaining duplicate cache tags with selectable width	19990525 711/3
US 5907698 A	Method and apparatus for characterizing static and dynamic operation of an architectural syst	19990525 716/6
US 5898687 A	Simulator, simulation and fabrication methods of semiconductor device and storage medium s	19990330 703/4
US 5886909 A	Defect diagnosis using simulation for IC yield improvement	19990323 716/4
US 5884062 A	Microprocessor with pipeline status integrity logic for handling multiple stage writeback except	19990316 712/218
US 5880971 A	Methodology for deriving executable low-level structural descriptions and valid physical implem	19990309 716/6
US 5880967 A	Minimization of circuit delay and power through transistor sizing	19990309 716/6
US 5878369 A	Golf course yardage and information system	19990302 701/215
US 5870308 A	Method and system for creating and validating low-level description of electronic design	19990209 716/18
US 5867399 A	System and method for creating and validating structural description of electronic system from	19990202 716/18
US 5867397 A	Method and apparatus for automated design of complex structures using genetic programming	19990202 703/14
US 5862149 A	Method of partitioning logic designs for automatic test pattern generation based on logical regi	19990119 714/726
US 5841670 A	Emulation devices, systems and methods with distributed control of clock domains	19981124 703/23
US 5825680 A	Method and apparatus for performing fast division	19981020 708/650
US 5822579 A	Microprocessor with dynamically controllable microcontroller condition selection	19981013 712/245
US 5812414 A	Method for performing simulation using a hardware logic emulation system	19980922 716/16
US 5805792 A	Emulation devices, systems, and methods	19980908 714/28
US 5802580 A	High performance digital electronic system architecture and memory circuit thereof	19980901 711/149
US 5801958 A	Method and system for creating and validating low level description of electronic design from t	19980901 716/18
US 5796623 A	Apparatus and method for performing computations with electrically reconfigurable logic devic	19980818 703/23
US 5774738 A	State machines	19980630 712/1
US 5764951 A	Methods for automatically pipelining loops	19980609 716/1
US 5764234 A	Trapezoidal partitioning method and apparatus therefor	19980609 345/423
US 5758123 A	Verification support system	19980526 703/22
US 5748872 A	Direct replacement cell fault tolerant architecture	19980505 714/11
US 5734581 A	Method for implementing tri-state nets in a logic emulation system	19980331 703/15
US 5719796 A	System for monitoring and analyzing manufacturing processes using statistical simulation wit	19980217 703/13
US 5712806 A	Optimized multiplexer structure for emulation systems	19980127 716/16
US 5706290 A	Method and apparatus including system architecture for multimedia communication	19980106 370/465

US 5694481 A	Automated design analysis system for generating circuit schematics from high magnification i	19971202 382/145
US 5692160 A	Temperature, process and voltage variant slew rate based power usage simulation and metho	19971125 703/23
US 5689431 A	Golf course yardage and information system	19971118 701/213
US 5678028 A	Hardware-software debugger using simulation speed enhancing techniques including skipping	19971014 703/22
US 5673199 A	Computer aided reuse tool	19970930 703/1
US 5663900 A	Electronic simulation and emulation system	19970902 716/17
US 5661662 A	Structures and methods for adding stimulus and response functions to a circuit design underg	19970826 716/16
US 5657241 A	Routing methods for use in a logic emulation system	19970812 716/16
US 5625803 A	Slew rate based power usage simulation and method	19970429 703/14
US 5625580 A	Hardware modeling system and method of use	19970429 703/21
US 5623418 A	System and method for creating and validating structural description of electronic system	19970422 716/1
US 5621652 A	System and method for verifying process models in integrated circuit process simulators	19970415 716/5